

INFORMATION DISCLOSURE CITATION

OMB No. 0651-0011

Atty. Docket No.	3180.0285	Appln. No.	09/931,916
Applicant	Mitsutake et al.		
Filing Date	August 20, 2001	Group:	2857

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
MCB	1207531	2/10/99	China			Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner <i>Nancy Catherine Baran</i>	Date Considered <i>10/13/04</i>
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Atty. Docket No. 03180.0285		Serial No. Not Yet Assigned					
Applicant Kunihiro MITSUTAKE et al.							
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
MCB	IKOTA, M. et al., "Discrimination of Clustered Defects on Wafers Using Statistical Methods", Proc. 1997 Second Int. Workshop Statistical Metrology, pp. 52-55.						
Examiner	Mary Catherine Brown			Date Considered 2/7/04			
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